

**Notice of References Cited**Application/Control No.  
09/923,604Applicant(s)/Patent Under  
Reexamination  
HAPKE, FRIEDRICHExaminer  
John P TrimmingsArt Unit  
2133

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	C	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Design of Scan-Based Path Delay Testable Sequential Circuits", Pramanick et al., October 17-21, 1993, IEEE, International Test Conference, pp962-971.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.